

General Description

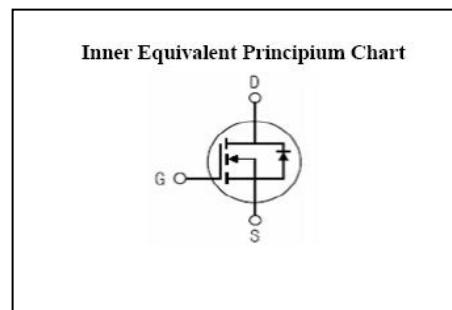
The HMM90N80 uses advanced trench technology and design to provide excellent RDS(ON) with low gate charge. It can be used in a wide variety of applications. The package form is Sot-227B, which accords with the RoHS standard.

V_{DSS}	800	V
I_D	90	A
P_D	1200	W
$R_{DS(ON)}$ type	35	$m\Omega$



Features

- FminiBLOC, with Aluminium Nitride Isolation
- International Standard Package
- Low Gate Charge and Rdson
- High Current Handling Capability



Applications

- Switch-Mode and Resonant-Mode Power Supplies
- DC-DC Converters
- PFC Circuits
- AC and DC Motor Drives
- Robotics and Servo Controls

Absolute ($T_c = 25^\circ C$ unless otherwise specified)

Symbol	Parameter	Rating	Units
V_{DSS}	Drain-to-Source Voltage	800	V
I_D	Continuous Drain Current	90	A
I_{DM}^{a1}	Pulsed Drain Current	270	A
V_{GS}	Gate-to-Source Voltage	± 30	V
E_{AS}^{a2}	Single Pulse Avalanche Energy	4000	mJ
P_D	Power Dissipation	1200	W
T_J, T_{stg}	Operating Junction and Storage Temperature Range	150, -55 to 150	$^\circ C$
T_L	MaximumTemperature for Soldering	300	$^\circ C$

Thermal Characteristics

Symbol	Parameter	Typ.	Units
$R_{\theta JC}$	Junction-to-Case	0.104	$^\circ C/W$

Electrical Characteristics (T_c= 25°C unless otherwise specified)

OFF Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
V _{DSS}	Drain to Source Breakdown Voltage	V _{GS} =0V, I _D =250μA	800	--	--	V
ΔBV _{DSS} /ΔT _J	Bvdss Temperature Coefficient	I _D =250uA, Reference 25°C	--	0.8	--	V/°C
I _{DSS}	Drain to Source Leakage Current	V _{DS} =800V, V _{GS} = 0V, T _a =25°C	--	--	50	μA
		V _{DS} =640V, V _{GS} =0V, T _a =125°C	--	--	5000	
I _{GSS(F)}	Gate to Source Forward Leakage	V _{GS} =+30V	--	--	800	nA
I _{GSS(R)}	Gate to Source Reverse Leakage	V _{GS} =-30V	--	--	-800	nA

ON Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
R _{DS(ON)}	Drain-to-Source On-Resistance	V _{GS} =10V, I _D =45A	--	35	41	mΩ
V _{GS(TH)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =250μA	2.0	--	4.0	V
Pulse width tp≤380μs, δ≤2%						

Dynamic Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
g _{fs}	Forward Transconductance	V _{DS} =10V, I _D =45A	--	62	--	S
C _{iss}	Input Capacitance	V _{GS} =0V, V _{DS} =25V	--	7.8	--	nF
C _{oss}	Output Capacitance	f=1.0MHz	--	2.3	--	
C _{rss}	Reverse Transfer Capacitance		--	0.13	--	

Resistive Switching Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
t _{d(ON)}	Turn-on Delay Time	I _D =45A, V _{DD} =400V	--	50	--	ns
t _r	Rise Time		--	25	--	
t _{d(OFF)}	Turn-Off Delay Time		--	170	--	
t _f	Fall Time		--	30	--	
Q _g	Total Gate Charge	I _D =45A, V _{DD} =400V V _{GS} =10V	--	155	--	nC
Q _{gs}	Gate to Source Charge		--	40	--	
Q _{gd}	Gate to Drain ("Miller")Charge		--	63	--	

Source-Drain Diode Characteristics

Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
I _S	Continuous Source Current (Body Diode)		--	--	90	A
I _{SM}	Maximum Pulsed Current (Body Diode)		--	--	360	A
V _{SD}	Diode Forward Voltage	I _S =90A, V _{GS} =0V	--	--	1.4	V
t _{rr}	Reverse Recovery Time	I _S =45A, T _j =25°C	--	350	--	ns
Q _{rr}	Reverse Recovery Charge	dI _F /dt=200A/us, V _{GS} =0V	--	20	--	uC

Pulse width tp≤380μs, δ≤2%

^{a1}: Repetitive rating; pulse width limited by maximum junction temperature

^{a2}: EAS condition : T_j=25°C, V_{DD}=50V, V_G=10V, L=0.5mH, R_g=25Ω

^{a3}: I_S≤I_{DM}, V_{DD}≤V_{DSS}, T_j≤150°C

Typical Characteristics

Fig. 1. Output Characteristics @ $T_J = 25^\circ\text{C}$

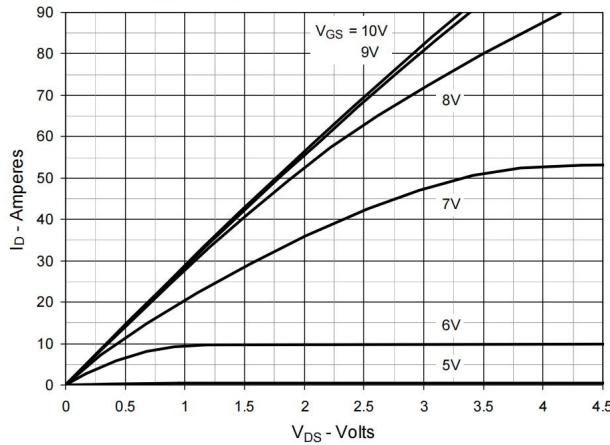


Fig. 2. Extended Output Characteristics @ $T_J = 25^\circ\text{C}$

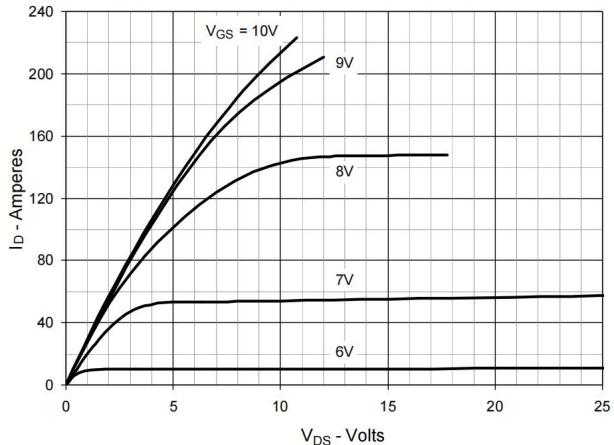


Fig. 3. Output Characteristics @ $T_J = 125^\circ\text{C}$

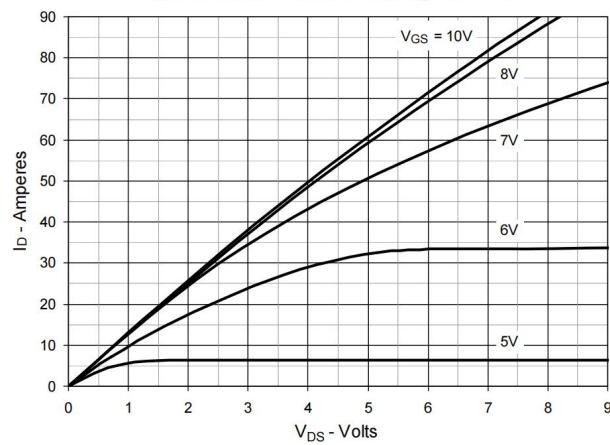


Fig. 4. $R_{DS(on)}$ Normalized to $I_D = 45\text{A}$ Value vs. Junction Temperature

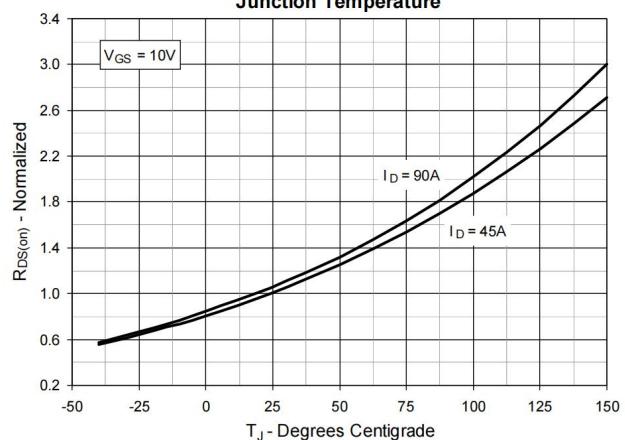


Fig. 5. $R_{DS(on)}$ Normalized to $I_D = 45\text{A}$ Value vs. Drain Current

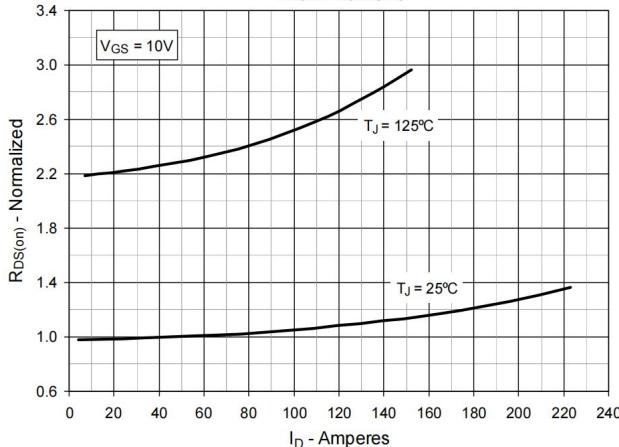


Fig. 6. Normalized Breakdown & Threshold Voltages vs. Junction Temperature

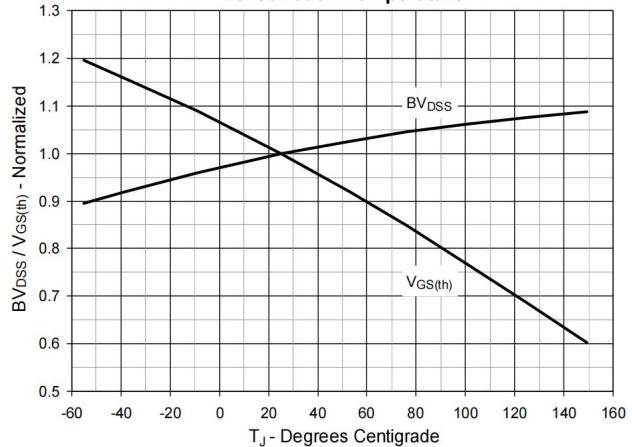
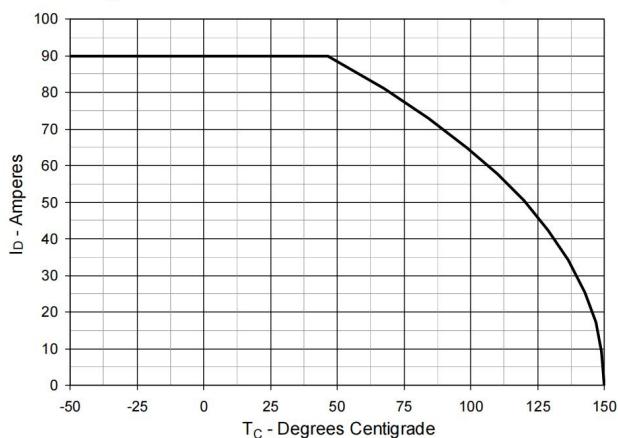
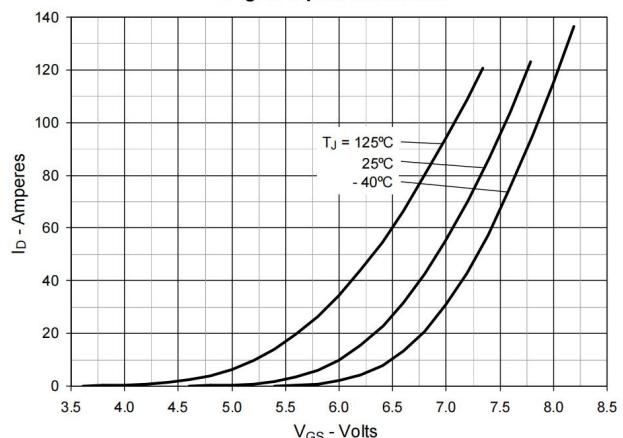
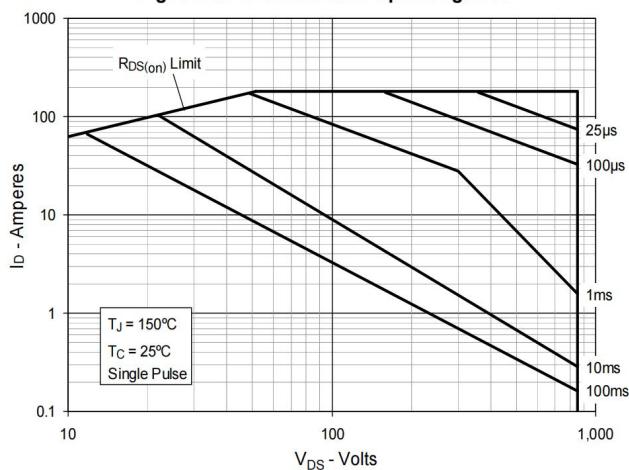
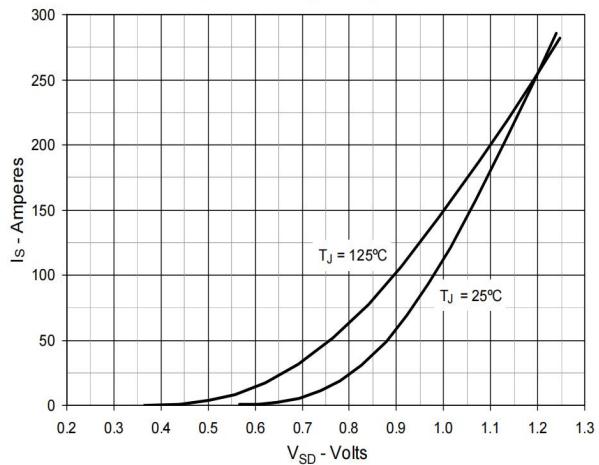


Fig. 7. Maximum Drain Current vs. Case Temperature

Fig. 8. Input Admittance

Fig. 9. Forward-Bias Safe Operating Area

Fig. 10. Forward Voltage Drop of Intrinsic Diode

Fig. 11. Maximum Transient Thermal Impedance
